

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/711,430	<b>Applicant(s)/Patent under Reexamination</b> HATHAWAY ET AL.
	<b>Examiner</b> TRONG PHAN	<b>Art Unit</b> 2827

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner